

L Number	Hits	Search Text	DB	Time stamp
-	3664260	signal generator\$1 and (test signal\$1 with (CUT or DUT or DFT or SUT))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/01/17 16:37
-	3632519	signal digitizer\$1 and ((extract\$3 near1 digital signal\$1) with (test and measurement) with (CUT or DUT or SUT or DFT))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/01/17 16:40
-	993807	(signal generator\$1 and (test signal\$1 with (CUT or DUT or DFT or SUT))) and (signal digitizer\$1 and ((extract\$3 near1 digital signal\$1) with (test and measurement) with (CUT or DUT or SUT or DFT)))	USPAT	2004/01/17 16:43
-	434730	integrated excitation/extraction system\$1 with (test and measurement with CUT near2 chip\$1)	USPAT	2004/01/17 16:43
-	273024	((signal generator\$1 and (test signal\$1 with (CUT or DUT or DFT or SUT))) and (signal digitizer\$1 and ((extract\$3 near1 digital signal\$1) with (test and measurement) with (CUT or DUT or SUT or DFT)))) and (integrated excitation/extraction system\$1 with (test and measurement with CUT near2 chip\$1))	USPAT	2004/01/17 16:46
-	694462	analog reconstruction filter\$1	USPAT	2004/01/17 16:46
-	877328	generat\$3 and (filtered test signal\$1)	USPAT	2004/01/17 16:47
-	391189	(analog reconstruction filter\$1) and (generat\$3 and (filtered test signal\$1))	USPAT	2004/01/17 16:47
-	994853	signal digitizer\$1	USPAT	2004/01/17 16:48
-	330623	((analog reconstruction filter\$1) and (generat\$3 and (filtered test signal\$1))) and (signal digitizer\$1)	USPAT	2004/01/17 16:48
-	609494	sequential shift register\$1	USPAT	2004/01/17 16:49
-	158551	((analog reconstruction filter\$1) and (generat\$3 and (filtered test signal\$1))) and (signal digitizer\$1) and (sequential shift register\$1)	USPAT	2004/01/17 16:49
-	62848	(((signal generator\$1 and (test signal\$1 with (CUT or DUT or DFT or SUT))) and (signal digitizer\$1 and ((extract\$3 near1 digital signal\$1) with (test and measurement) with (CUT or DUT or SUT or DFT)))) and (integrated excitation/extraction system\$1 with (test and measurement with CUT near2 chip\$1))) and (((analog reconstruction filter\$1) and (generat\$3 and (filtered test signal\$1))) and (signal digitizer\$1)) and (sequential shift register\$1))	USPAT	2004/01/17 16:50
-	2412567	reference voltage generator\$1	USPAT	2004/01/17 16:50
-	2555541	variable DC reference voltage signal\$1	USPAT	2004/01/17 16:51
-	2385085	(reference voltage generator\$1) with (variable DC reference voltage signal\$1)	USPAT	2004/01/17 16:52
-	61684	(((signal generator\$1 and (test signal\$1 with (CUT or DUT or DFT or SUT))) and (signal digitizer\$1 and ((extract\$3 near1 digital signal\$1) with (test and measurement) with (CUT or DUT or SUT or DFT)))) and (integrated excitation/extraction system\$1 with (test and measurement with CUT near2 chip\$1))) and (((analog reconstruction filter\$1) and (generat\$3 and (filtered test signal\$1))) and (signal digitizer\$1)) and (sequential shift register\$1)) and ((reference voltage generator\$1) with (variable DC reference voltage signal\$1))	USPAT	2004/01/17 16:53
-	122493	comparator\$1 and (response signal\$1 with reference voltage\$1)	USPAT	2004/01/17 16:53
-	161318	extract\$3 and (digital signal\$1)	USPAT	2004/01/17 16:54
-	19051	(comparator\$1 and (response signal\$1 with reference voltage\$1)) and (extract\$3 and (digital signal\$1))	USPAT	2004/01/17 16:54

	4636	(((((signal generator\$1 and (test signal\$1 with (CUT or DUT or DFT or SUT))) and (signal digitizer\$1 and ((extract\$3 near1 digital signal\$1) with (test and measurement) with (CUT or DUT or SUT or DFT)))) and (integrated excitation/extraction system\$1 with (test and measurement with CUT near2 chip\$1))) and (((analog reconstruction filter\$1) and (generat\$3 and (filtered test signal\$1))) and (signal digitizer\$1)) and (sequential shift register\$1))) and ((reference voltage generator\$1) with (variable DC reference voltage signal\$1))) and ((comparator\$1 and (response signal\$! with reference voltage\$1)) and (extract\$3 and (digital signal\$1)))	USPAT	2004/01/17 16:55
	3205	714/718.ccls. or 714/740.ccls. or 714/738.ccls. or 714/736.ccls. or 714/725.ccls. or 714/724.ccls. or 714/721.ccls. or 714/799.ccls. or 324/?..ccls.	USPAT	2004/01/17 16:58
	29	(((((signal generator\$1 and (test signal\$1 with (CUT or DUT or DFT or SUT))) and (signal digitizer\$1 and ((extract\$3 near1 digital signal\$1) with (test and measurement) with (CUT or DUT or SUT or DFT)))) and (integrated excitation/extraction system\$1 with (test and measurement with CUT near2 chip\$1))) and (((analog reconstruction filter\$1) and (generat\$3 and (filtered test signal\$1))) and (signal digitizer\$1)) and (sequential shift register\$1))) and ((reference voltage generator\$1) with (variable DC reference voltage signal\$1))) and ((comparator\$1 and (response signal\$! with reference voltage\$1)) and (extract\$3 and (digital signal\$1))) and (714/718.ccls. or 714/740.ccls. or 714/738.ccls. or 714/736.ccls. or 714/725.ccls. or 714/724.ccls. or 714/721.ccls. or 714/799.ccls. or 324/?..ccls.)	USPAT	2004/01/17 16:59
	761319	memory circuit\$1 with sequential shift register\$1	USPAT	2004/01/17 16:59
	1084012	signal generator\$1	USPAT	2004/01/17 17:00
	260010	(signal generator\$1) with (memory circuit\$1 with sequential shift register\$1)	USPAT	2004/01/17 17:00
	25	((signal generator\$1) with (memory circuit\$1 with sequential shift register\$1)) and ((((((signal generator\$1 and (test signal\$1 with (CUT or DUT or DFT or SUT))) and (signal digitizer\$1 and ((extract\$3 near1 digital signal\$1) with (test and measurement) with (CUT or DUT or SUT or DFT)))) and (integrated excitation/extraction system\$1 with (test and measurement with CUT near2 chip\$1))) and (((analog reconstruction filter\$1) and (generat\$3 and (filtered test signal\$1))) and (signal digitizer\$1)) and (sequential shift register\$1))) and ((reference voltage generator\$1) with (variable DC reference voltage signal\$1))) and ((comparator\$1 and (response signal\$! with reference voltage\$1)) and (extract\$3 and (digital signal\$1))) and (714/718.ccls. or 714/740.ccls. or 714/738.ccls. or 714/736.ccls. or 714/725.ccls. or 714/724.ccls. or 714/721.ccls. or 714/799.ccls. or 324/?..ccls.))	USPAT	2004/01/17 17:01
	1394636	pulse density modulation signal\$1	USPAT	2004/01/17 17:01
	1183716	program\$4 with reference voltage signal\$1	USPAT	2004/01/17 17:02
	566545	averaging circuit\$1 with passive RC filter\$1	USPAT	2004/01/17 17:03
	336750	(program\$4 with reference voltage signal\$1) and (averaging circuit\$1 with passive RC filter\$1)	USPAT	2004/01/17 17:03
	322985	(pulse density modulation signal\$1) and ((program\$4 with reference voltage signal\$1) and (averaging circuit\$1 with passive RC filter\$1))	USPAT	2004/01/17 17:04
	1070706	periodic signal\$1	USPAT	2004/01/17 17:05
	309641	(periodic signal\$1) and ((pulse density modulation signal\$1) and ((program\$4 with reference voltage signal\$1) and (averaging circuit\$1 with passive RC filter\$1)))	USPAT	2004/01/17 17:06

	8	<p>(((signal generator\$1) with (memory circuit\$1 with sequential shift register\$1)) and ((((((signal generator\$1 and (test signal\$1 with (CUT or DUT or DFT or SUT))) and (signal digitizer\$1 and ((extract\$3 near1 digital signal\$1) with (test and measurement) with (CUT or DUT or SUT or DFT)))) and (integrated excitation/extraction system\$1 with (test and measurement with CUT near2 chip\$1))) and (((analog reconstruction filter\$1) and (generat\$3 and (filtered test signal\$1))) and (signal digitizer\$1)) and (sequential shift register\$1))) and ((reference voltage generator\$1) with (variable DC reference voltage signal\$1))) and ((comparator\$1 and (response signal\$1 with reference voltage\$1)) and (extract\$3 and (digital signal\$1)))) and (714/718.ccls. or 714/740.ccls. or 714/738.ccls. or 714/736.ccls. or 714/725.ccls. or 714/724.ccls. or 714/721.ccls. or 714/799.ccls. or 324/?ccls.)) and ((periodic signal\$1) and ((pulse density modulation signal\$1) and ((program\$4 with reference voltage signal\$1) and (averaging circuit\$1 with passive RC filter\$1))))</p>	USPAT	2004/01/17 17:08
1488645	7	<p>single scan-chain integrated near2 chip\$1</p> <p>(((signal generator\$1) with (memory circuit\$1 with sequential shift register\$1)) and ((((((signal generator\$1 and (test signal\$1 with (CUT or DUT or DFT or SUT))) and (signal digitizer\$1 and ((extract\$3 near1 digital signal\$1) with (test and measurement) with (CUT or DUT or SUT or DFT)))) and (integrated excitation/extraction system\$1 with (test and measurement with CUT near2 chip\$1))) and (((analog reconstruction filter\$1) and (generat\$3 and (filtered test signal\$1))) and (signal digitizer\$1)) and (sequential shift register\$1))) and ((reference voltage generator\$1) with (variable DC reference voltage signal\$1))) and ((comparator\$1 and (response signal\$1 with reference voltage\$1)) and (extract\$3 and (digital signal\$1)))) and (714/718.ccls. or 714/740.ccls. or 714/738.ccls. or 714/736.ccls. or 714/725.ccls. or 714/724.ccls. or 714/721.ccls. or 714/799.ccls. or 324/?ccls.)) and ((periodic signal\$1) and ((pulse density modulation signal\$1) and ((program\$4 with reference voltage signal\$1) and (averaging circuit\$1 with passive RC filter\$1)))) and (single scan-chain integrated near2 chip\$1)</p>	USPAT USPAT	2004/01/17 17:08 2004/01/17 17:09
995254	7	<p>programming near1 signal generator\$1 with test signal\$1</p> <p>passively filtering with periodic bit-stream\$1</p> <p>((((signal generator\$1) with (memory circuit\$1 with sequential shift register\$1)) and ((((((signal generator\$1 and (test signal\$1 with (CUT or DUT or DFT or SUT))) and (signal digitizer\$1 and ((extract\$3 near1 digital signal\$1) with (test and measurement) with (CUT or DUT or SUT or DFT)))) and (integrated excitation/extraction system\$1 with (test and measurement with CUT near2 chip\$1))) and (((analog reconstruction filter\$1) and (generat\$3 and (filtered test signal\$1))) and (signal digitizer\$1)) and (sequential shift register\$1))) and ((reference voltage generator\$1) with (variable DC reference voltage signal\$1))) and ((comparator\$1 and (response signal\$1 with reference voltage\$1)) and (extract\$3 and (digital signal\$1)))) and (714/718.ccls. or 714/740.ccls. or 714/738.ccls. or 714/736.ccls. or 714/725.ccls. or 714/724.ccls. or 714/721.ccls. or 714/799.ccls. or 324/?ccls.)) and ((periodic signal\$1) and ((pulse density modulation signal\$1) and ((program\$4 with reference voltage signal\$1) and (averaging circuit\$1 with passive RC filter\$1)))) and (single scan-chain integrated near2 chip\$1)) and (programming near1 signal generator\$1 with test signal\$1)</p>	USPAT	2004/01/17 17:10
13507	7		USPAT	2004/01/17 17:11
			USPAT	2004/01/17 17:11
1389024		<p>channel encoder\$1 and (channel encoding input information bit\$1 with outputting encoded symbol\$1)</p>	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/01/19 14:00